

Network setup tool

SHOP FLOOR SYSTEM SUPPORT

- Supports text file, data base, and DLL interfaces.
- S/N and operator ID check.
- Multi-data exchange protocol.

THE MOST COST-EFFECTIVE TEST STRATEGY

Non-Multiplexing Pin Design, Driver/Receiver Ratio 1:1

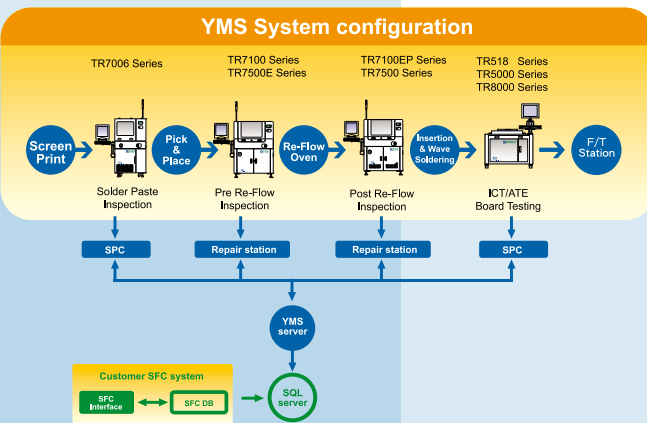
- Optimized Nail Placement with 1:1 Ratio Flexibility.
- ECNs do not require moving existing wires in your fixture.
- 1:1 Driver/Receiver pins provide for the fastest test program development and debug solution available.

GENRAD AND TERADYNE CONVERSION TOOLKITS

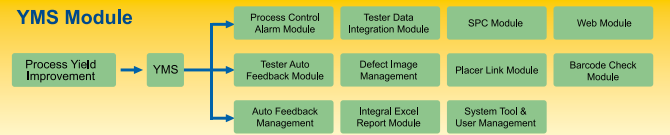
No need for a new TRI fixture for your existing GenRad or Teradyne fixtures.

PCBA YIELD MANAGEMENT SYSTEM

TRI's Yield Management System (YMS) is an omni-directional, integrated solution for today's manufacturing environment. It gathers and analyzes data from all TRI systems on the shop floor and delivers it as a user-friendly report format. TRI's YMS is a flexible system to meet the present and future needs of high-volume manufacturers.



YMS Module



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GENERAL

Test Points Expandable to 3584, TR8100LLV Expandable to 5632
 PC Compatible Computer
 Operating System Microsoft Windows 2000/XP
 Power Requirement 200-240V/ 100-120V 50/60Hz: 3 KVA
 Fixture Type Vacuum Type Option: Pneumatic Type

ANALOG HARDWARE

Measurement Switching Matrix
 6-wire measurement
 2 Programmable Voltage Source
 1 Programmable High Voltage Source
 1 Programmable Current Source
Arbitrary Waveform Generator(AWG)
 2 Digitally synthesized stimulus sources configurable
 Frequency range 0 ~100KHz, Resolution: 0.15Hz
Analog Measurement
 AC Voltmeter 0 ~100V
 DC Voltmeter 0 ~±100V
 DC Ammeter 1uA ~ 160mA

Analog Source
 DC 0 ~ ±12V, AC 0 ~ 7Vrms
 DC 0 ~ ±45V, 50mA Max.
 DC 0 ~ ±200mA

Component Measurement Capability
 Resistance 1 ohm~40M ohm
 Capacitance AC 1pF~150uF
 Capacitance DC 3uF~40mF
 Inductance 1uH~ 60H

DIGITAL HARDWARE

Non-Multiplexing 1:1 system per pin architecture
 Pin Drivers Programmable levels 0.5V to 4 V
 Pin Receivers Programmable levels -5V to 5V
 Sink/Source Current 500mA
 Pull-up / pull-down Resistor 4.7K
 DUT Power Supplies 5V@5A, 3.3V@5A, 12V@5A, 0.2~20V@3A, -3~-20V@3A
 NAND Tree Facilities with BGA Test Support accuracy pin open for BGA/VLSI chip
 Agilent TestJet Technology Vectorless Open Circuit Detection
 On- Board Programming of Flash & EEPROM Memories Support the Binary Code Input Without Coding Environment
 MAC Address Programming Supports MAC Address Programming with MAC address being supplied from server

OPTIONS

Boundary Scan B-Scan Chain Test, B-Scan Cluster Test & B-Scan Virtual Nails Test Facilities
 DUT Power Supplies Programmable 5V@20A, 8V@12.5A, 20V@5A, 35V@3A, 50V@2A, 60V@1.6A, 100V@1A
 Intel Socket Test Technology The highest test coverage for CPU socket
 Fixture Converter Kits available for GenRad &Teradyne

DIMENSIONS / WEIGHT

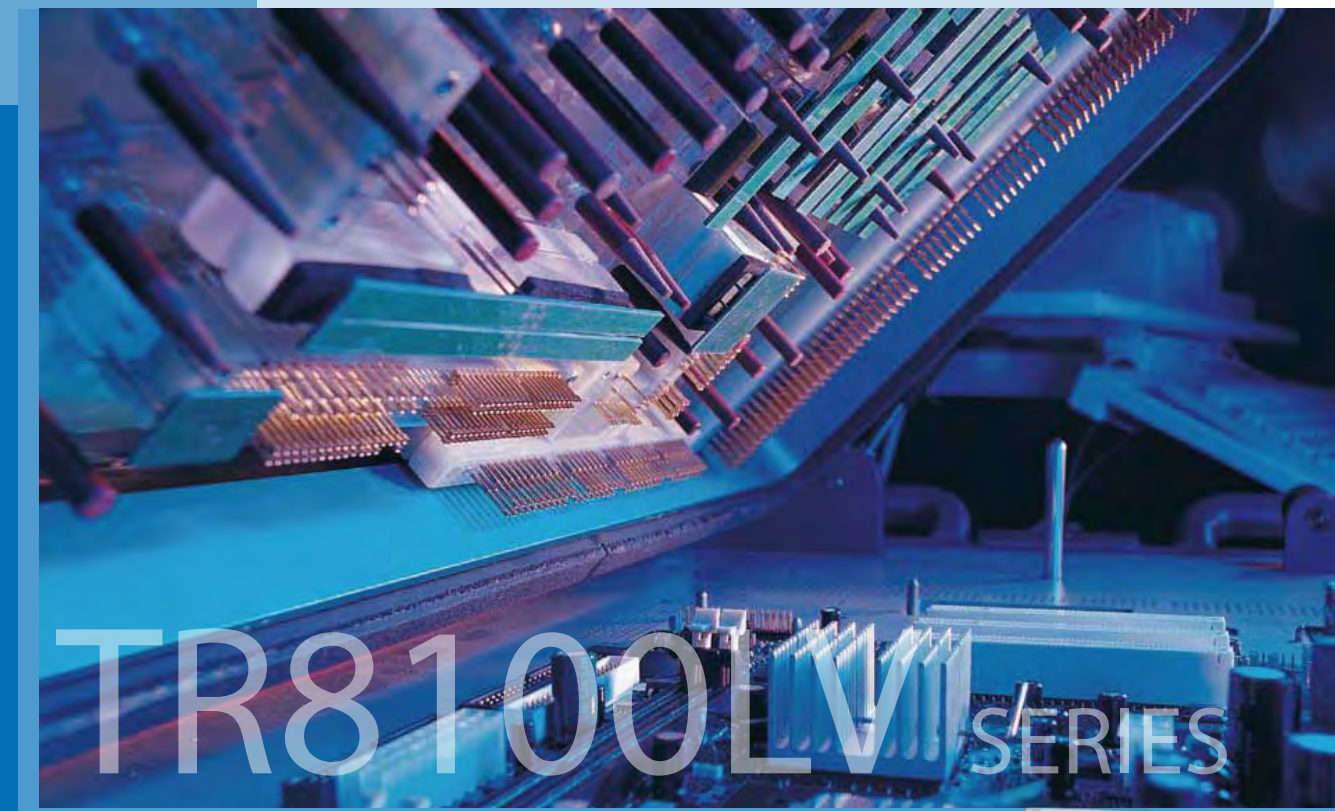
TR8100LV 1150 mm(W) x 850 mm(D) x 790 mm(H) / 227kg (43" x 34 " x 31 " / 500lbs.)
 TR8100LLV 1550 mm(W) x 850 mm(D) x 790 mm(H) / 330kg (54" x 34 " x 31 " / 728lbs.)

POWERFUL SOFTWARE ENVIRONMENT

Microsoft Windows operating system software. User-friendly interface
 Automatic Test Program Generator
 Automatic disable generator of surrounding components
 Automatic test generation with Auto-learning of open/shorts using IC Clamping Diode and Agilent TestJet technology
 Auto Debug of passive components.
 Built in system self-diagnostic function
 Paperless repair station & real-time process monitoring
 Time selectable quality management and statistical reports
 Board view instantly displays failing device and pin

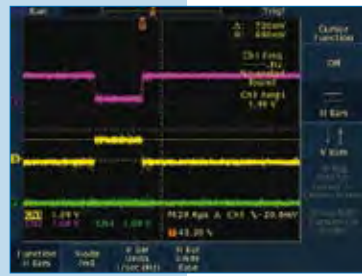
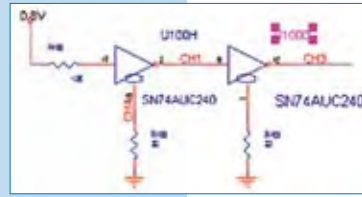
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T R 8 1 0 0 L V I C T



- HIGH-PERFORMANCE, HIGH THROUGHPUT IN-CIRCUIT TESTER
- HIGH FAULT COVERAGE TEST SOLUTION
- EASY AND FAST TEST PROGRAM DEVELOPMENT
- FRIENDLY USER INTERFACE DESIGN
- LOW-VOLTAGE SOLUTION





THE SOLUTION FOR TESTING LOW VOLTAGE TECHNOLOGIES

TR8100LV provides an ultra-low output impedance to enhance low-voltage backdriving capability.

- SN74AUC240 is a low-voltage device where VCC=0.8v.
- TR8100LV meets the specification of the SN74AUC240 in low-voltage testing requirement.

FAST AND EASY TEST PROGRAM DEVELOPMENT

Test Program Development Flowchart.

EASY-TO-USE ON-BOARD PROGRAMMING SOFTWARE MODULES

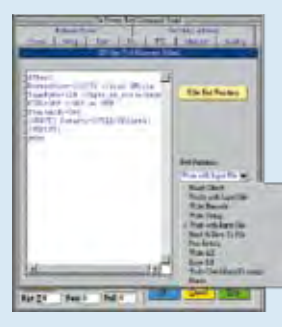
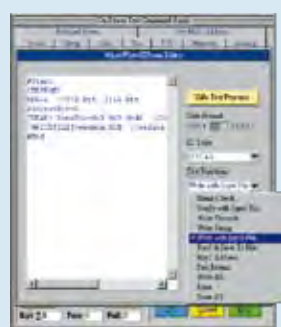
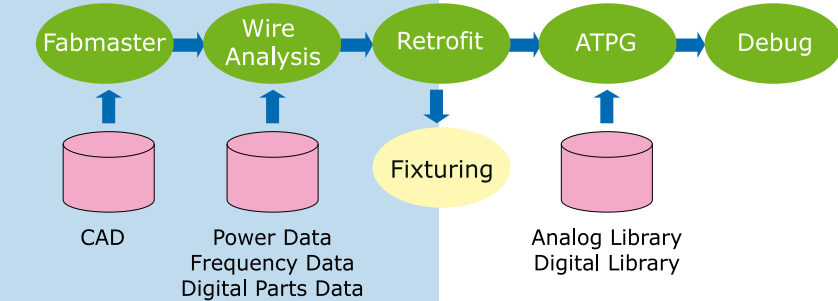
Modularized memory algorithms provide convenient On-Board Programming function.

Flash Programming

- Supports a macro command language
- Supports conditional programming
- Supports multi vendor programming
- Menu-based debug tool

Serial Device Programming

- Menu-based test program generation
- Supports conditional programming
- Supports multi vendor programming



EEPROM Programming

SPI Programming

ISP Programming

NO TEST ACCESS SOLUTIONS

- TRI ToggleScan™ Test: Combines Boundary-Scan test and vectorless test to reduce the physical test probes. Includes Connector Test, Socket Test, Resistor Array Test, Capacitor Array Test, & Non-Boundary-Scan Chip Test.
- Drive-Through Test: Overpowers the resistors and capacitors to control and sense signals.
- CPU-Socket Test: Applies CSS (CPU Socket Sensor) on the top of the CPU to test the CPU without any physical test probes.
- Boundary Scan Test : The TR8100LV implements IEEE1149.1 & 1149.6 Boundary-Scan testing beginning with TRI's ABSTG (Automatic Boundary Scan Test program Generator). This auto-generates test programs and reporting for different kinds of test categories, such as individual boundary-scan device tests, boundary-scan cluster test, boundary-scan devices chain test and virtual nails test.

- Optimal Test Analyzer (OTA): Powerful software that performs line optimal analysis for cost efficiency and to decrease testing time.

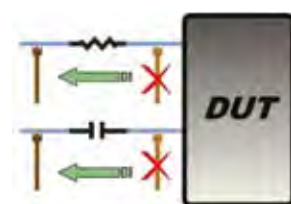
INTEGRATED ASSET SCANWORKS BOUNDARY-SCAN TECHNOLOGY*

Manufacturers will be able to globally deploy solutions from both Asset and TRI. The optional ScanWorks card solution integrated with TRI systems provides substantial cost savings.

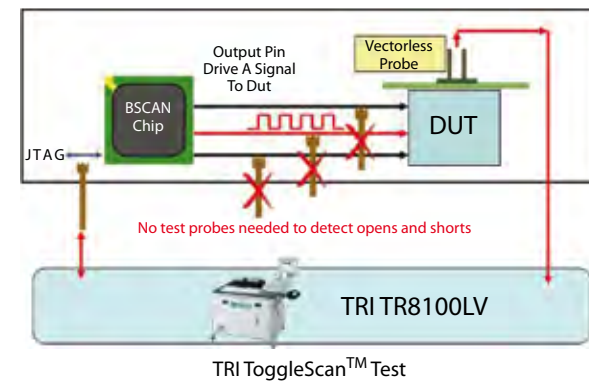
(*)Optional



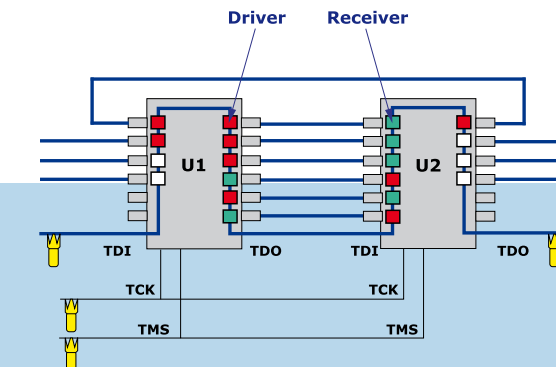
BSTG



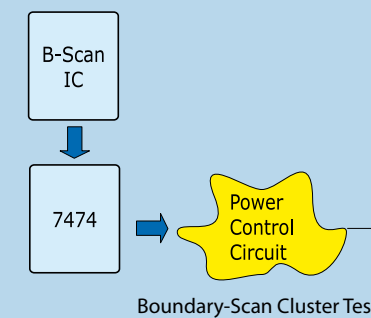
Drive-Through Test



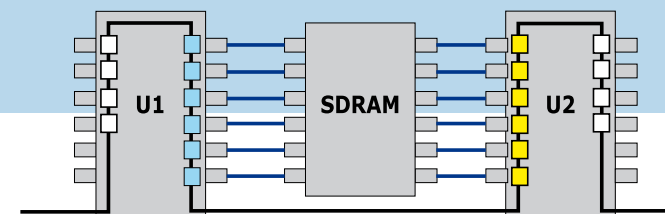
TRI ToggleScan™ Test



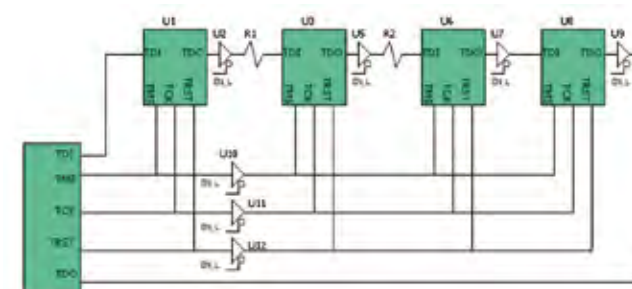
Boundary-Scan Chain Test



Boundary-Scan Cluster Test



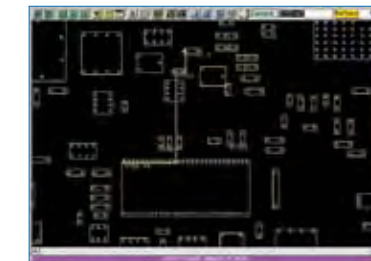
Boundary-Scan Virtual Nails Test



Multi-Chip BSDL Test



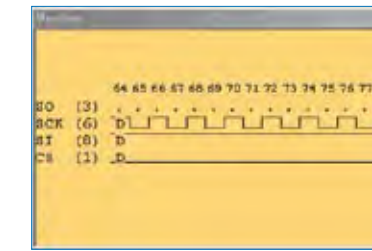
Table-based test program editor



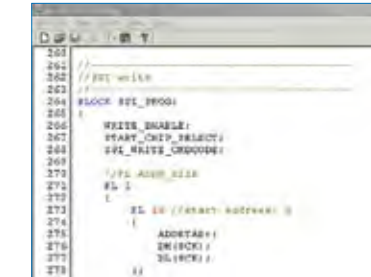
Board view with trace display capability



Simple test GUI



Waveform display



Color syntax program editor

USER-FRIENDLY INTERFACE

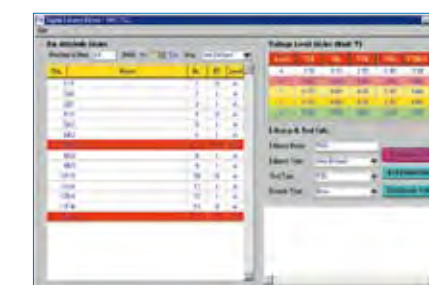
TR8100LV provides a simple-to-understand flexible interface

- Color syntax program editor
- C-like test language
- Editable waveform display tool
- Integrated development environment

EASY MODEL DEVELOPMENT

Narrative library structure for fast and easy edits

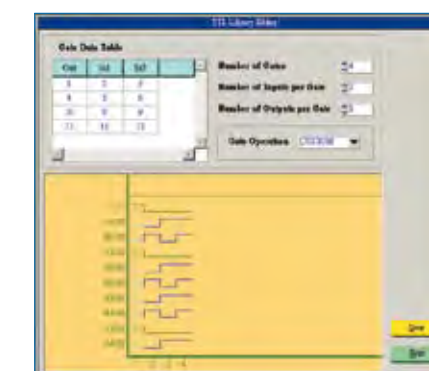
- Import pin information
- Library syntax check
- Integrated GUI for all device types



Import pin information



Library



Library edit tool